

NN511661 / NN511667 series

EDO (Hyper Page) Mode

CMOS 64K × 16bit Dynamic RAM

NPNX

DESCRIPTION

The NN511661/1667 series is a high performance CMOS Dynamic Random Access Memory organized as 65,536 words by 16 bits. The NN511661/1667 series is fabricated with advanced CMOS technology and designed with innovative design techniques resulting in high speed, extremely low power and wide operating margins at both component and system levels.

The NN511661/1667 series features an EDO (Hyper Page) mode operation in which a high speed read, write or read-write is performed on any column address along a row address.

An extremely short row address capture time and an asynchronous column address decoder relax the timing constraints associated with address multiplexing.

Refresh is accomplished by performing $\overline{\text{RAS}}$ only refresh cycles, hidden refresh cycles, $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh cycles, or normal read or write cycles on the 256 address combinations of A0 to A7 during a 4 ms period.

Multiplexed address inputs permit the NN511661 series to be packaged in a standard 40-pin plastic SOJ, 44-pin plastic TSOP TYPEII. The package sizes provide high system bit densities and are compatible with widely available automated testing and insertion equipment. System level features include single power supply of 5V $\pm$ 10% tolerance and direct interface with high performance TTL logic families.

FEATURES

- 65,536 × 16 bit Organization
- Single 5V $\pm$ 10% Power Supply
- Performance Ranges

Parameter	-40	-45	-50	-60	-70
Max. RAS Access Time (t_{RAC})	40ns	45ns	50ns	60ns	70ns
Max. CAS Access Time (t_{CAC})	10ns	15ns	15ns	15ns	20ns
Max. Column Address Access Time (t_{AA})	21ns	23ns	25ns	30ns	35ns
Min. Read/Write Cycle Time (t_{RC})	70ns	80ns	90ns	110ns	130ns

- EDO (Hyper Page) Mode Operation
- Separate CAS (UCAS, LCAS) for Byte Selection
- Byte Write Mode Operation
- Low Power Operation
 - Low Standby Current (CMOS level inputs)
 - Standard 1mA
 - L version 50 μ A
- 256 Refresh Cycles
 - Standard distributed across 4ms
 - L version distributed across 32ms
- Self Refresh Mode (L version)
- All inputs/Outputs and Clocks fully TTL and CMOS compatible
- Refresh Modes
 - RAS only
 - $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$
 - Hidden Refresh
- High Reliability Package
 - Plastic 40pin SOJ (P40SJ-2B)
 - Plastic 44pin TSOP TYPEII (P44/40TP-3B)

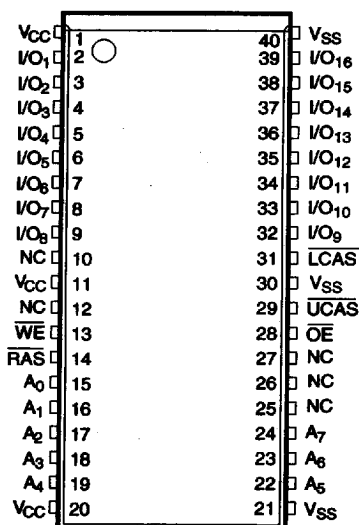
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NN511661 : N092-FXX-00132 Rev.1.1
NN511667 : N092-FXX-00099 Rev.1.1

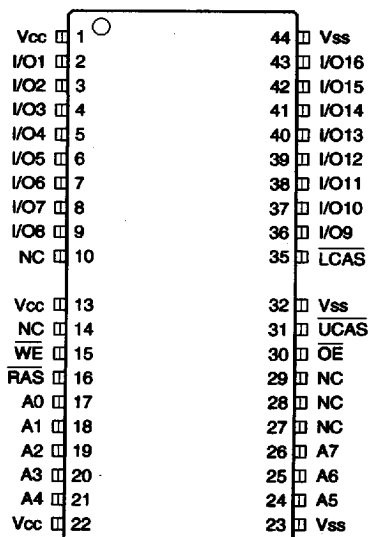
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NIPPON STEEL SEMICONDUCTOR CORPORATION
AUG.1997

PIN CONFIGURATION (TOP VIEW)
(NN511661)



40-pin SOJ (400mil)
P40SJ-2B

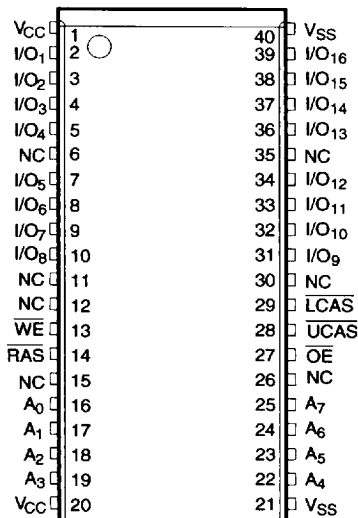


44/40-pin TSOP TYPE (II)
(400mil)
P44/40TP-3B

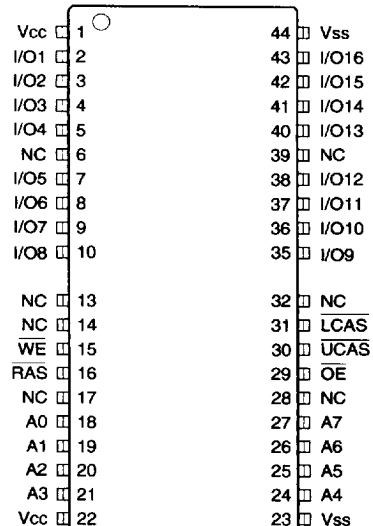
PIN NAMES

A0~A7	Address Inputs
RAS	Row Address Strobe
UCAS	Column Address Strobe Upper Byte Control
LCAS	Column Address Strobe Lower Byte Control
OE	Output Enable
I/O1~I/O16	Data-in / Data-out
WE	Write Enable
V _{CC}	+5V Supply
V _{SS}	Ground
NC	No Connection

PIN CONFIGURATION (TOP VIEW) (NN511667)



40-pin SOJ (400mil)
P40SJ-2B



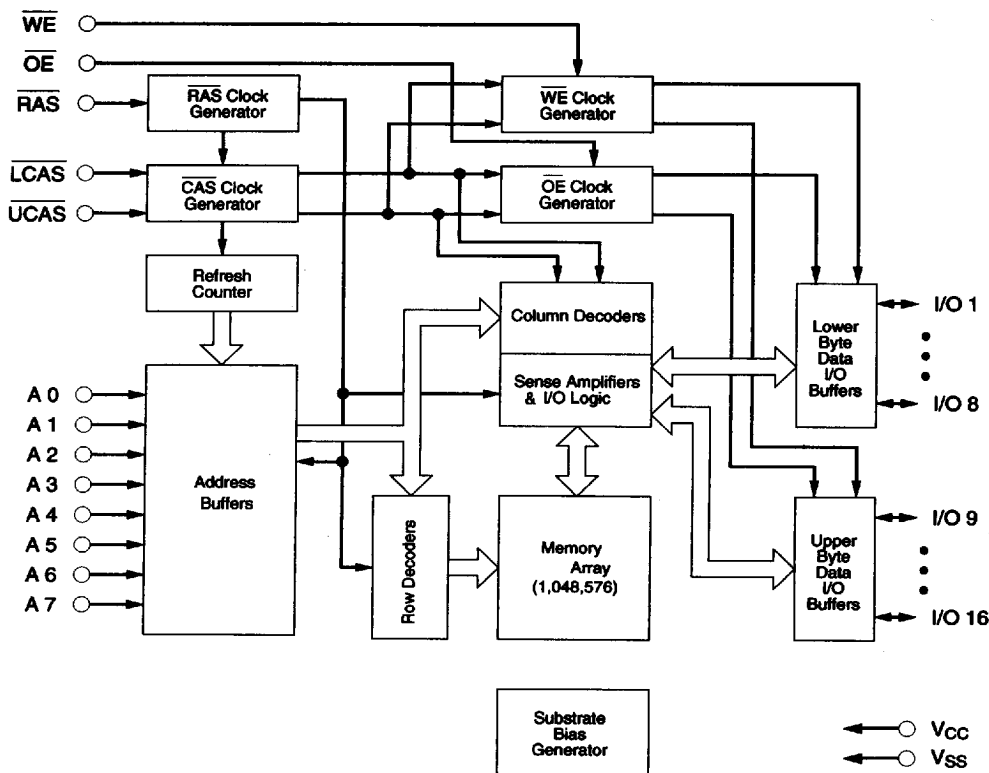
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V _{SS}	Ground
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FUNCTIONAL BLOCK DIAGRAM



ABSOLUTE MAXIMUM RATINGS

RATING	SYMBOL	VALUE	UNIT
Voltage on Any Pin Relative to V _{SS}	V _{IN} , V _{OUT}	-1 to 7	V
Voltage on V _{CC} Relative to V _{SS}	V _{CC}	-1 to 7	V
Storage Temperature (Plastic)	T _{STG}	-55 to +125	°C
Power Dissipation	P _D	1.0	W
Ambient Operating Temperature	T _A	0 to +70	°C
Short Circuit Output Current	I _{OUT}	50	mA

Permanent device damage can occur if absolute maximum ratings are exceeded. Functional operation should be restricted to the conditions as detailed in the operational sections of this data sheet. Exposure to absolute maximum rating conditions for extended periods can affect device reliability.

DC OPERATING CONDITIONS

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNIT
V _{CC}	Supply Voltage	4.5	5.0	5.5	V
V _{SS}	Supply Voltage	0	0	0	V
V _{IH}	Input High Voltage, All Inputs	2.4	—	6.5	V
V _{IL}	Input Low Voltage, All Inputs	-1.0	—	0.8	V

Note: All voltage values in this data sheet are with respect to V_{SS} unless otherwise specified.

DC ELECTRICAL CHARACTERISTICS (0°C ≤ Ta ≤ 70°C, V_{CC} = 5.0V ±10%)

SYMBOL	PARAMETER	SPEED	MIN.	MAX.	UNIT	TEST CONDITIONS	NOTES
I _{CC1}	Operating Current	-40		180	mA	t _{RC} = t _{RC} (min.) RAS, CAS, Address cycling	1, 2
		-45		160	mA		
		-50		140	mA		
		-60		120	mA		
		-70		100	mA		
I _{CC2}	Standby Current			1.0	mA	RAS = CAS ≥ (V _{CC} - 0.2V)	
				2.0	mA	RAS = CAS ≥ V _{IH}	
	Standby Current (L version)			50	μA	RAS = CAS ≥ (V _{CC} - 0.2V) All other inputs are stable at (V _{CC} - 0.2V) or (V _{SS} + 0.2V)	
I _{CC3}	Refresh Current (RAS only refresh)	-40		180	mA	t _{RC} = t _{RC} (min.) RAS cycling, CAS = V _{IH}	1
		-45		160	mA		
		-50		140	mA		
		-60		120	mA		
		-70		100	mA		
I _{CC4}	EDO (Hyper Page) Mode Current	-40		180	mA	t _{HPC} = t _{HPC} (min.) RAS = V _{IL} CAS, Address cycling	1,2
		-45		160	mA		
		-50		140	mA		
		-60		120	mA		
		-70		100	mA		
I _{CC5}	Refresh Current (CAS before RAS refresh)	-40		165	mA	t _{RC} = t _{RC} (min.) RAS, CAS cycling	1
		-45		145	mA		
		-50		125	mA		
		-60		105	mA		
		-70		85	mA		
I _{CC6}	Refresh Current (L version : CAS before RAS refresh)			150	μA	256 cycles / 32ms t _{RAS} ≤ 200ns, WE ≥ (V _{CC} - 0.2V) All other inputs are stable at (V _{CC} - 0.2V) or (V _{SS} + 0.2V)	
I _{CC7}	Self Refresh Mode Current (L version)			100	μA	RAS = CAS ≤ (V _{SS} + 0.2V) All other input high levels are (V _{CC} - 0.2V) or input low levels are (V _{SS} + 0.2V)	
I _{L1}	Input Leakage Current (Any input pin)		-10	10	μA	0V ≤ V _{IH} ≤ 5.5V, Others = 0V	
I _{L0}	Output Leakage Current (For high impedance state)		-10	10	μA	RAS ≥ V _{IH} (min.), CAS ≥ V _{IH} (min.) 0V ≤ V _{OUT} ≤ 5.5V	
V _{OH}	Output High Voltage		2.4		V	I _{OH} = -5.0 mA	
V _{OL}	Output Low Voltage			0.4	V	I _{OL} = 4.2 mA	

Notes: 1. I_{CC1}, I_{CC3}, I_{CC4} and I_{CC5} depend on cycle rate.

2. I_{CC1} and I_{CC4} depend on output loading. Specified values are obtained with the outputs open.

CAPACITANCE (0°C ≤ Ta ≤ 70°C, V_{CC} = 5.0V ±10%, f = 1MHz)

SYMBOL	PARAMETER	MIN.	MAX.	UNIT
C _{IN1}	Address(A0 ~ A7)	—	5	pF
C _{IN2}	RAS, UCAS, LCAS, WE, OE	—	5	pF
C _{OUT}	I/O1 ~ I/O16	—	7	pF

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A.C. OPERATING CONDITIONS

Test conditions : $V_{IH}/V_{IL} = 2.4/0.8V$ $V_{OH}/V_{OL} = 2.0/0.8V$ output loading $C_L = 50pF + 1TTL$
 Operating conditions : ($0^\circ C \leq T_a \leq 70^\circ C$, $V_{CC} = 5V \pm 10\%$, $V_{SS} = 0V$) (NOTES 3, 4, 5)

NO.	NOTES		PARAMETER	-40		-45		-50		-60		-70		UNIT	NOTE
	JEDEC	STD.		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
1	t_{CL1QV}	t_{CAC}	Access Time from CAS	—	10	—	15	—	15	—	15	—	20	ns	6,13
2	t_{CH2QV}	t_{CPA}	Access Time from CAS Precharge	—	23	—	28	—	30	—	35	—	40	ns	13,14
3	t_{AVQV}	t_{AA}	Access Time from Column Address	—	21	—	23	—	25	—	30	—	35	ns	7,13
4	t_{RL1QV}	t_{RAC}	Access Time from RAS	—	40	—	45	—	50	—	60	—	70	ns	6,7
5	t_{RL1CH1}	t_{CSH}	CAS Hold Time	30	—	30	—	35	—	45	—	55	—	ns	
6	t_{RL1CX}	t_{CHS}	CAS Hold Time (Self Refresh Mode)	-50	—	-50	—	-50	—	-50	—	-50	—	ns	
7	t_{RL1CH1}	t_{CHR}	CAS Hold Time (CAS before RAS Refresh)	8	—	8	—	8	—	10	—	10	—	ns	
8	t_{CH2CL2}	t_{CPN}	CAS Precharge Time (CAS before RAS Refresh)	7	—	8	—	8	—	10	—	10	—	ns	
9	t_{CH2CL2}	t_{CP}	CAS Precharge Time (EDO (Hyper Page) Mode)	5	—	5	—	5	—	5	—	5	—	ns	14
10	t_{CL1CH1}	t_{CAS}	CAS Pulse Width	6	100K	8	100K	8	100K	10	100K	15	100K	ns	
11	t_{CL1RL2}	t_{CSR}	CAS Setup Time (CAS before RAS Refresh)	5	—	5	—	5	—	5	—	5	—	ns	
12	t_{CL1QX}	t_{CLZ}	CAS to Output in Low-Z	0	—	0	—	0	—	0	—	0	—	ns	8
13	t_{CH2RL2}	t_{CRP}	CAS to RAS Precharge Time	5	—	5	—	5	—	5	—	5	—	ns	
14	t_{CL1WL2}	t_{CWD}	CAS to WE Delay Time	40	—	45	—	45	—	45	—	50	—	ns	11
15	t_{CL1AX}	t_{CAH}	Column Address Hold Time	6	—	8	—	8	—	10	—	15	—	ns	
16	t_{RL1AX}	t_{AR}	Column Address Hold Time Referenced to RAS	28	—	30	—	35	—	40	—	40	—	ns	
17	t_{AVCL2}	t_{ASC}	Column Address Setup Time	0	—	0	—	0	—	0	—	0	—	ns	14
18	t_{AVCH1}	t_{CAL}	Column Address to CAS Lead Time	11	—	13	—	13	—	18	—	23	—	ns	
19	t_{AVRH1}	t_{RAL}	Column Address to RAS Lead Time	20	—	22	—	27	—	30	—	35	—	ns	
20	t_{AVWL2}	t_{AWD}	Column Address to WE Delay Time	47	—	52	—	57	—	60	—	65	—	ns	11
21	t_{CL1DX} t_{WL1DX}	t_{DH}	Data Hold Time	6	—	8	—	8	—	10	—	10	—	ns	12
22	t_{CL2QX}	t_{DHC}	Data Output Hold Time (EDO (Hyper Page) Mode)	0	—	0	—	0	—	0	—	0	—	ns	
23	t_{DVCL2} t_{DVL2}	t_{DS}	Data Setup Time	0	—	0	—	0	—	0	—	0	—	ns	12
24	t_{OL1QV}	t_{OEA}	OE Access Time	—	13	—	13	—	15	—	15	—	20	ns	
25	t_{WL1OL2}	t_{OEH}	OE Command Hold Time	5	—	13	—	13	—	15	—	20	—	ns	
26	t_{GH2GL2}	t_{OPZ}	OE Pulse Width for Output Disable When CAS High	5	—	5	—	7	—	7	—	7	—	ns	
27	t_{GL1CH1}	t_{OCS}	OE Setup Time to CAS High	5	—	5	—	7	—	7	—	7	—	ns	
28	t_{GL1RH1}	t_{ORS}	OE Setup Time to RAS High	5	—	5	—	7	—	7	—	7	—	ns	
29	t_{CH2QV}	t_{OED}	OE to Data Delay Time	6	—	7	—	8	—	10	—	10	—	ns	
30	t_{GL2QX}	t_{OLZ}	OE to Output in low-Z	0	—	0	—	0	—	0	—	0	—	ns	
31	t_{CH2QZ}	t_{OFF}	Output Buffer Turn-off Delay Time	0	10	0	12	0	13	0	15	0	15	ns	10
32	t_{OH2QX}	t_{OEZ}	Output Buffer Turn-off Delay Time Referenced to OE	0	8	0	10	0	10	0	15	0	15	ns	
33	t_{RHQZ}	t_{OFFR}	Output Buffer Turn-off Delay Time Referenced to RAS	0	10	0	12	0	13	0	15	0	15	ns	16

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NO.	SYMBOL		PARAMETER	-40		-45		-50		-60		-70		UNIT	NOTE
	JEDEC	STD.		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MAX.	MIN.		
34	t _{WL2OZ}	t _{WEZ}	Output Buffer Turn-off Delay Time Referenced to WE	0	12	0	12	0	13	0	15	0	15	ns	
35	t _{CL1RH1}	t _{RSH}	RAS Hold Time	8	—	13	—	13	—	15	—	20	—	ns	
36	t _{OL1RH1}	t _{ROH}	RAS Hold Time Referenced to OE	8	—	8	—	10	—	10	—	10	—	ns	
37	t _{CH2RH1}	t _{RHCP}	RAS Hold Time Referenced CAS Precharge	26	—	28	—	30	—	35	—	40	—	ns	
38	t _{RH2RL2}	t _{RP}	RAS Precharge Time	25	—	25	—	25	—	30	—	40	—	ns	
39	t _{RH2RL2}	t _{RPS}	RAS Precharge Time (Self Refresh Mode)	70	—	80	—	90	—	110	—	130	—	ns	
40	t _{RL1RH1}	t _{RAS}	RAS Pulse Width	40	100K	45	100K	50	100K	60	100K	70	100K	ns	
41	t _{RL1RH1}	t _{RASS}	RAS Pulse Width (Self Refresh Mode)	300	—	300	—	300	—	300	—	300	—	μs	
42	t _{RL1RH1}	t _{RASP}	RAS Pulse Width (EDO (Hyper Page) Mode)	40	100K	45	100K	50	100K	60	100K	70	100K	ns	
43	t _{RL1CL1}	t _{RCD}	RAS to CAS Delay Time	12	30	13	30	13	35	13	45	13	50	ns	6
44	t _{RH2CL2}	t _{RPC}	RAS to CAS Precharge Time	0	—	10	—	10	—	10	—	10	—	ns	
45	t _{RL1AV}	t _{RAD}	RAS to Column Address Delay Time	10	19	11	20	11	23	11	30	11	35	ns	7
46	t _{RL2OX}	t _{RLZ}	RAS To Output in Low-Z	0	—	0	—	0	—	0	—	0	—	ns	
47	t _{RL1WL2}	t _{RWD}	RAS to WE Delay Time	50	—	60	—	80	—	90	—	100	—	ns	11
48	t _{CH2WL2}	t _{RCH}	Read Command Hold Time	0	—	0	—	0	—	0	—	0	—	ns	9
49	t _{RH2WL2}	t _{RRH}	Read Command Hold Time Referenced to RAS	5	—	5	—	5	—	5	—	10	—	ns	9
50	t _{WH2CL2}	t _{RCS}	Read Command Setup Time	0	—	0	—	0	—	0	—	0	—	ns	
51	t _{RL2RL2}	t _{RC}	Random Read or Write Cycle Time	70	—	80	—	90	—	110	—	130	—	ns	
52	t _{CL2CL2}	t _{HPC}	Read or Write Cycle Time (EDO (Hyper Page) Mode)	15	—	20	—	20	—	25	—	30	—	ns	13,14
53	t _{RL2RL2}	t _{RMW}	Read-Modify-Write Cycle Time	100	—	120	—	125	—	145	—	185	—	ns	
54	t _{CL2CL2}	t _{PRMW}	Read-Modify-Write Cycle Time (EDO (Hyper Page) Mode)	55	—	57	—	57	—	66	—	95	—	ns	13,14
55	t _{REF}	t _{REF}	Refresh Period	—	4	—	4	—	4	—	4	—	4	ms	15
56	t _{RL1AX}	t _{RAH}	Row Address Hold Time	8	—	8	—	8	—	8	—	8	—	ns	
57	t _{AVRL2}	t _{ASR}	Row Address Setup Time	0	—	0	—	0	—	0	—	0	—	ns	
58	t _T	t _T	Transition Time (Rise and Fall)	2	50	2	50	2	50	2	50	2	50	ns	4,5
59	t _{WL1WH1}	t _{WPZ}	WE Pulse Width for Disable When CAS High	5	—	5	—	7	—	7	—	7	—	ns	
60	t _{CL1WH1}	t _{WCH}	Write Command Hold Time	6	—	8	—	10	—	10	—	15	—	ns	
61	t _{WL1WH1}	t _{WP}	Write Command Pulse Width	6	—	8	—	10	—	10	—	15	—	ns	
62	t _{WL1CL2}	t _{WCS}	Write Command Setup Time	0	—	0	—	0	—	0	—	0	—	ns	11
63	t _{WL1CH1}	t _{CWL}	Write Command to CAS Lead Time	6	—	8	—	8	—	15	—	20	—	ns	
64	t _{WL1RH1}	t _{RWL}	Write Command to RAS Lead Time	8	—	8	—	8	—	10	—	20	—	ns	

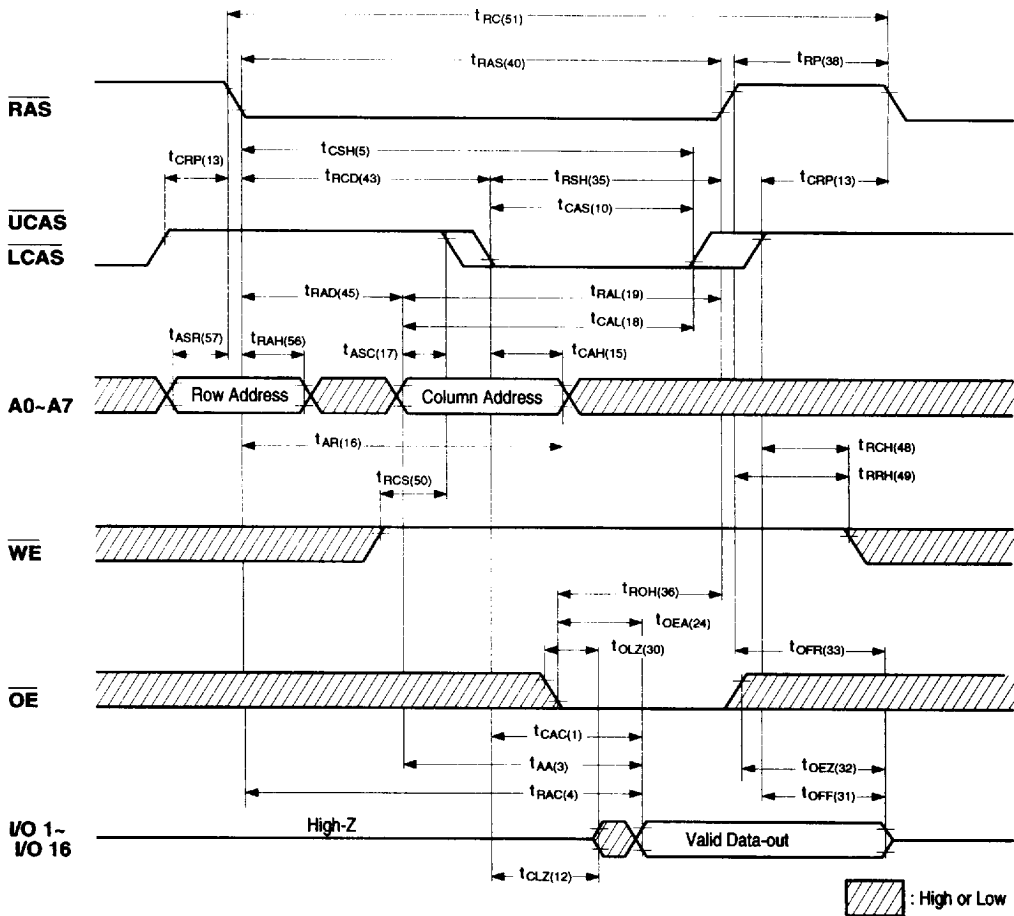
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Notes:

3. Eight Initialization Cycles are required following a 200 μ s pause after Power Up. These Initialization Cycles may consist of any combination of the following : RAS only refresh Cycles, Read Cycles, Write Cycles, CAS before RAS refresh Cycles.
4. AC measurements assume $t_T=3ns$.
5. $V_{IH}(min.)$ and $V_{IL}(max.)$ are reference levels for measuring timing of input signals. Also, transition times are measured between V_{IH} and V_{IL} .
6. Operation within the $t_{RCD}(max.)$ limit ensures that $t_{RAC}(max.)$ can be met. $t_{RCD}(max.)$ is specified as a reference point only. If t_{RCD} is greater than the specified $t_{RCD}(max.)$ limit, then access time is controlled by t_{CAC} .
7. Operation within the $t_{RAD}(max.)$ limit ensures that $t_{RAC}(max.)$ can be met. $t_{RAD}(max.)$ is specified as a reference point only. If t_{RAD} is greater than the specified $t_{RAD}(max.)$ limit, then access time is controlled by t_{AA} .
8. Assumes three state test load (5pF and a 220 ohm to 1.3V Thevenin equivalent).
9. Either t_{RCH} or t_{RRH} must be satisfied for a read cycle.
10. $t_{OFF}(max.)$ defines the time at which the output achieves an open circuit condition and is not referenced to output voltage levels.
11. t_{WCS} , t_{RWD} , t_{CWD} and t_{AWD} are not restrictive operating parameters. They are included in the data sheet as electrical characteristics only. If $t_{WCS} \geq t_{WCS}(min.)$, the cycle is an early write cycle and data-out pins will remain open circuit (high impedance) throughout the entire cycle. If $t_{RWD} \geq t_{RWD}(min.)$, $t_{CWD} \geq t_{CWD}(min.)$ and $t_{AWD} \geq t_{AWD}(min.)$, the cycle is a read-modify-write cycle and the data-out will contain data read from the selected cell. If neither of the above conditions is satisfied, the condition of the data-out (at access time) is indeterminate.
12. These parameters are referenced to $\overline{CAS}$ leading edge in early write cycles and to $\overline{WE}$ leading edge in read-modify-write cycles.
13. Access time is determined by the longer of t_{AA} , t_{CAC} , or t_{CPA} .
14. $t_{ASC} \geq t_{CP}$ to achieve $t_{PC}(min.)$ and $t_{CPA}(max.)$ values.
15. $t_{REF}=32msec$ for Long Refresh version (L version).
16. t_{OFF} applies only when $\overline{CAS}$ is high.

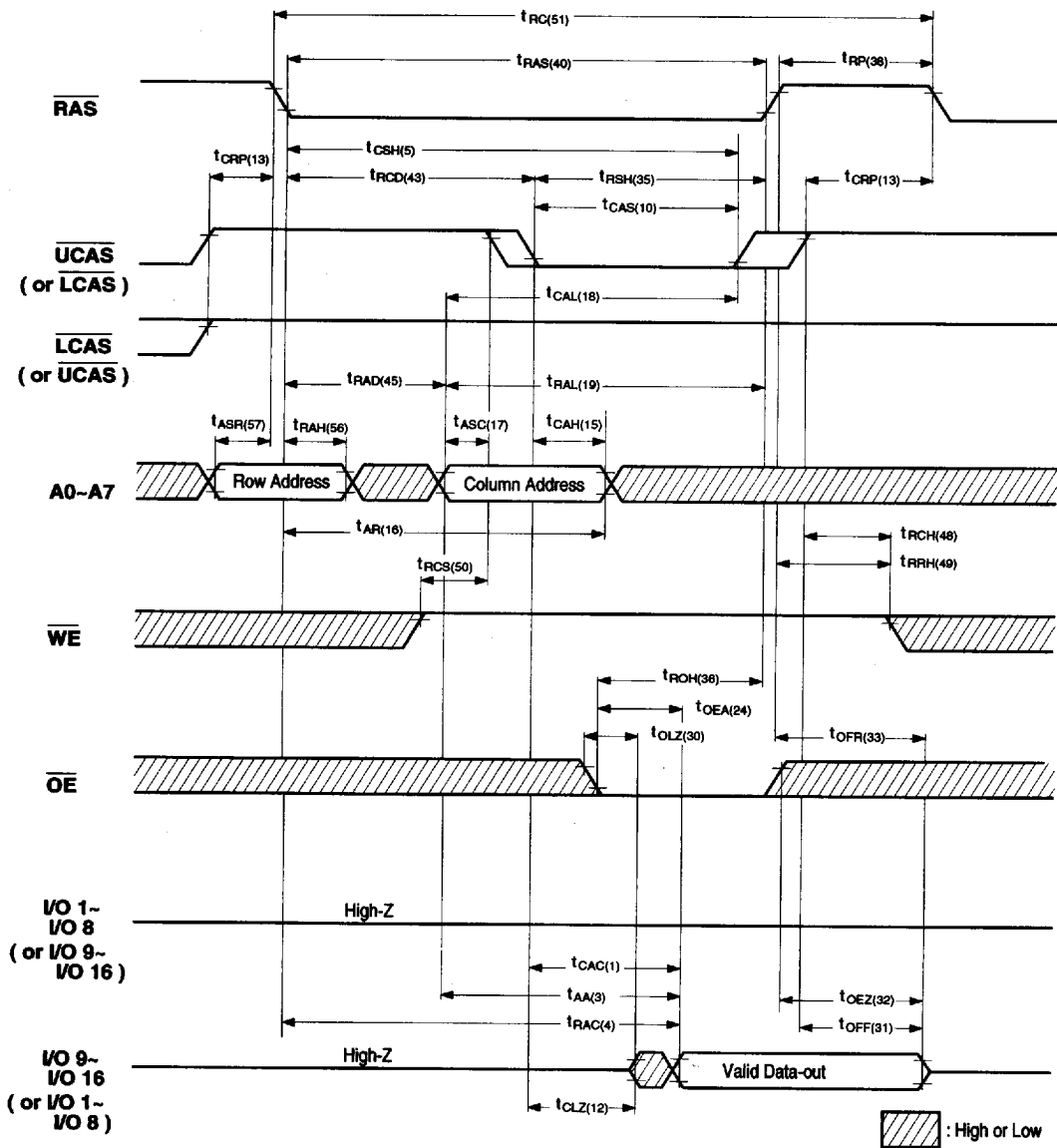
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WORD READ CYCLE



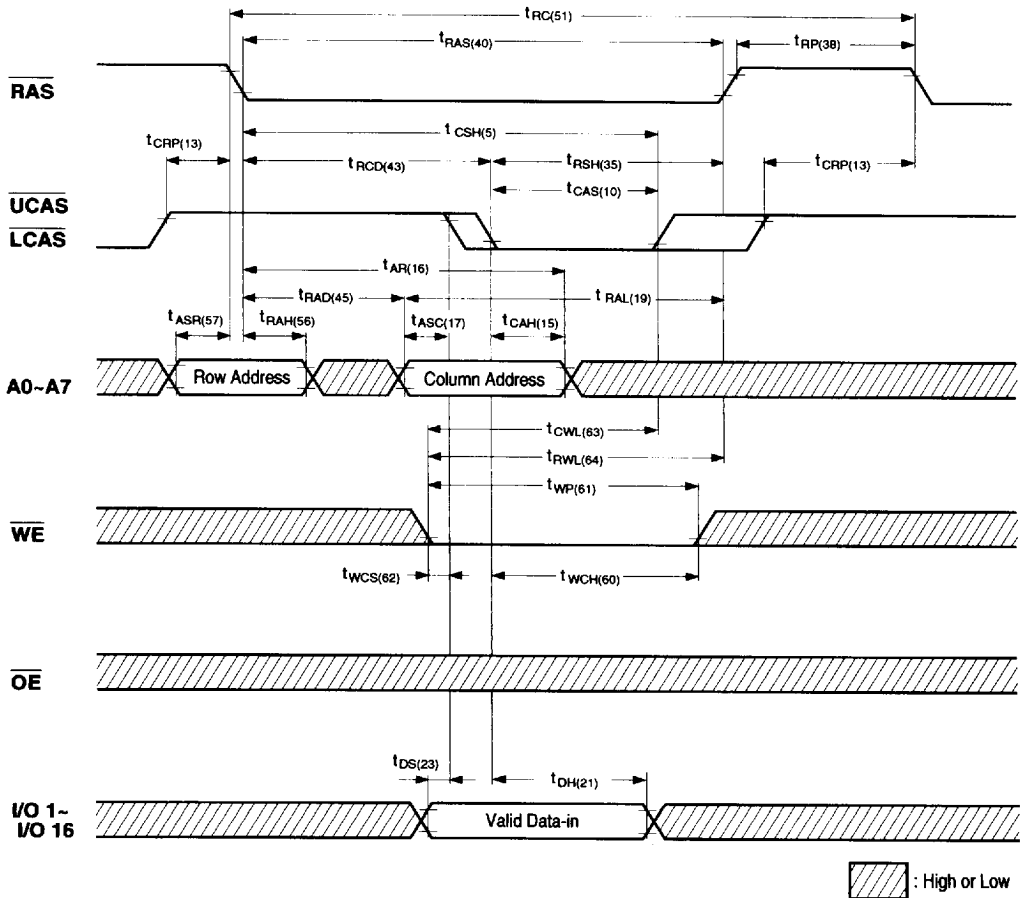
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BYTE READ CYCLE



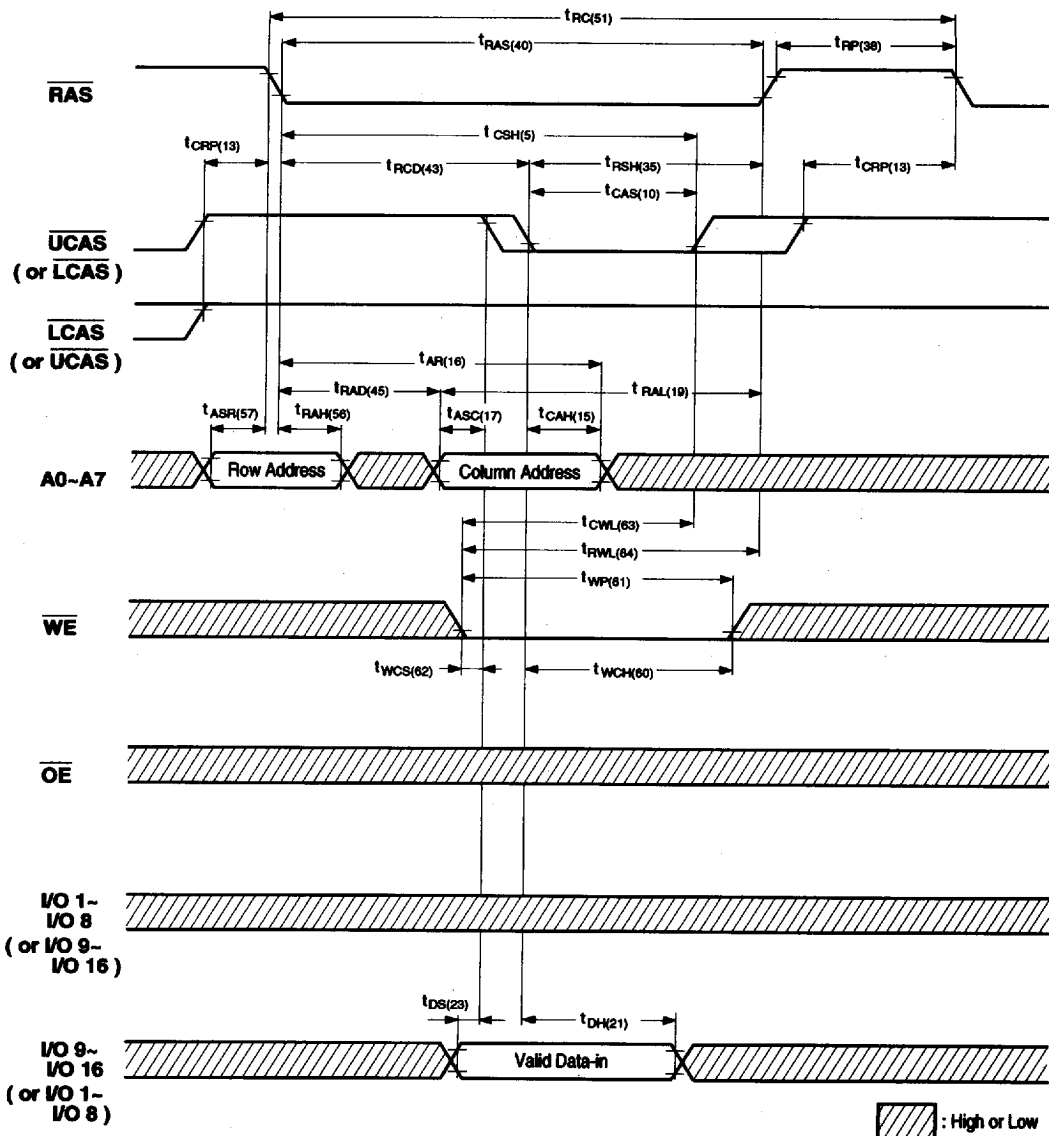
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WORD WRITE CYCLE (EARLY WRITE)



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BYTE WRITE CYCLE (EARLY WRITE)

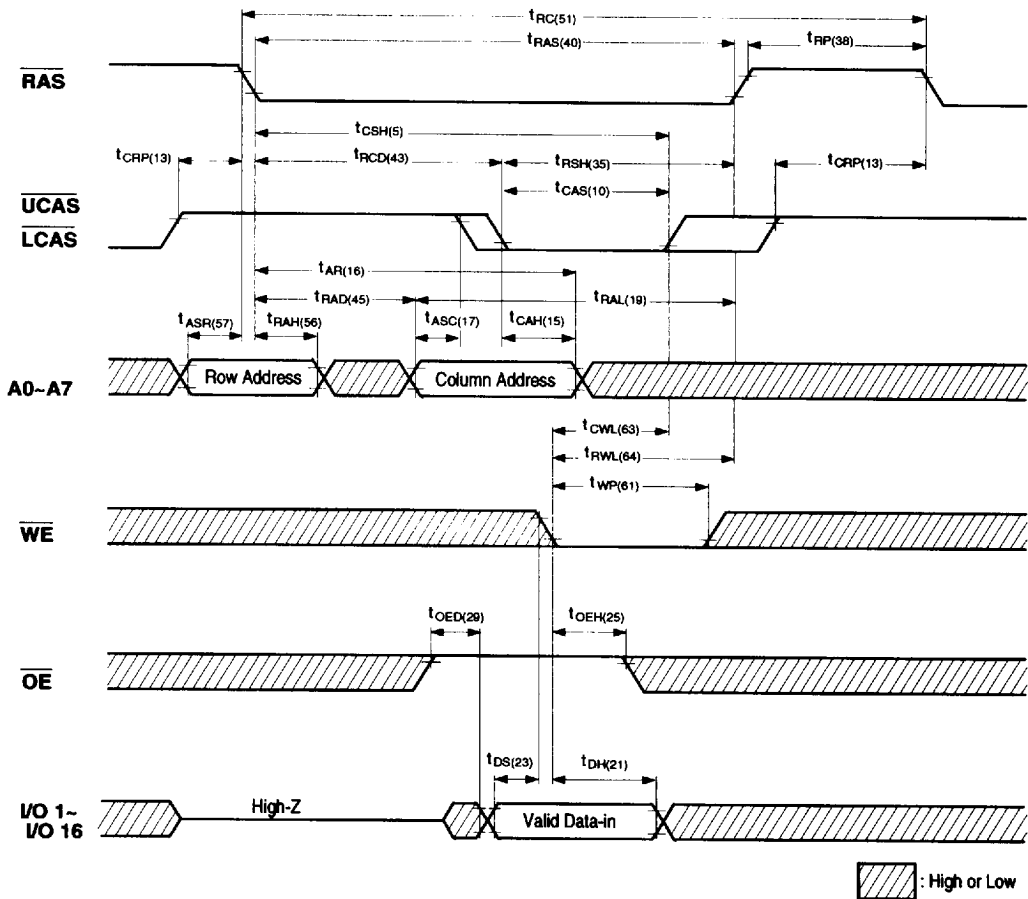


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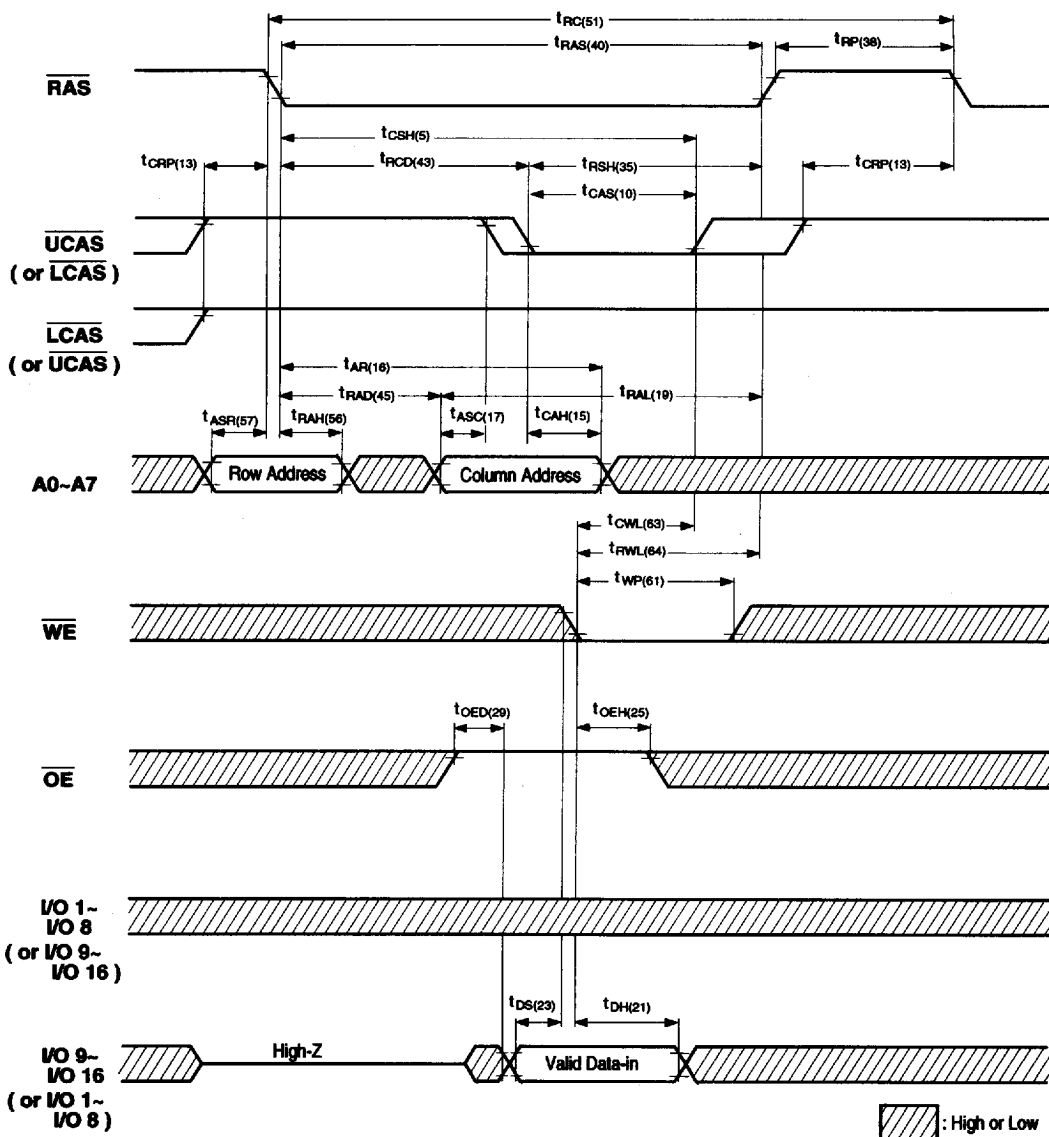
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WORD WRITE CYCLE ($\overline{\text{OE}}$ -CONTROLLED WRITE)

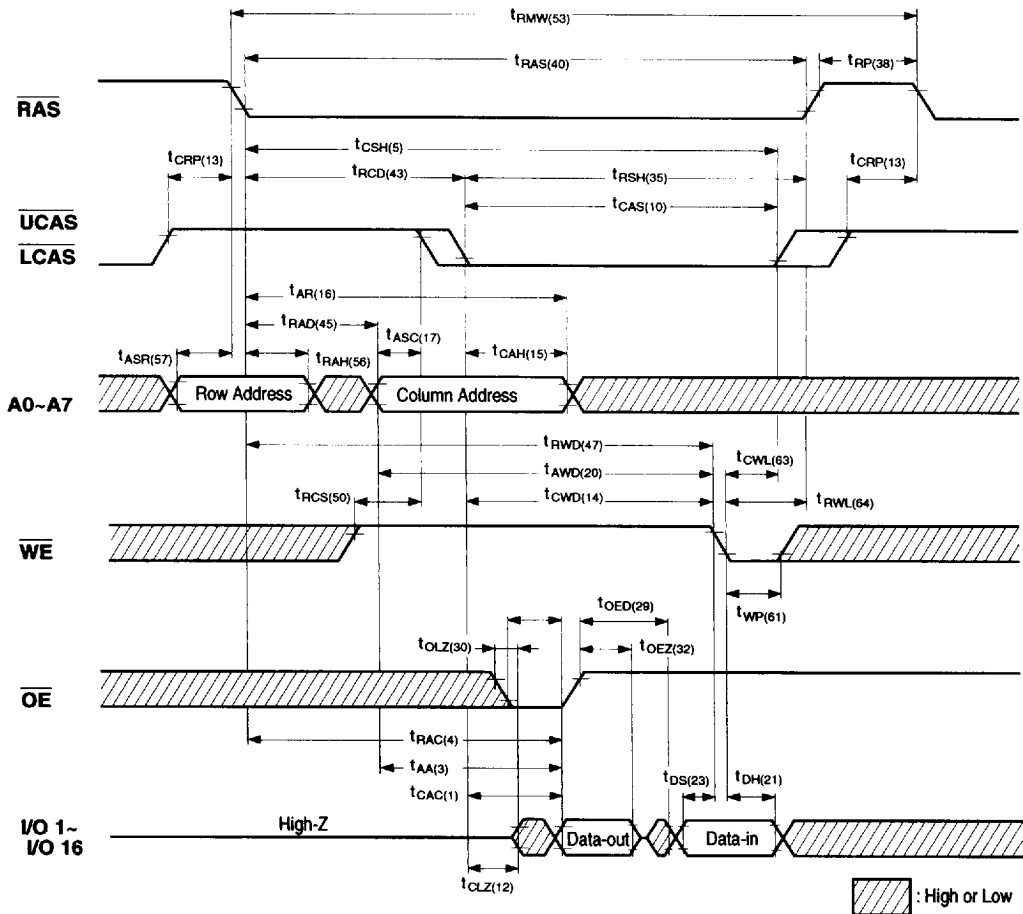


BYTE WRITE CYCLE ($\overline{\text{OE}}$ -CONTROLLED WRITE)



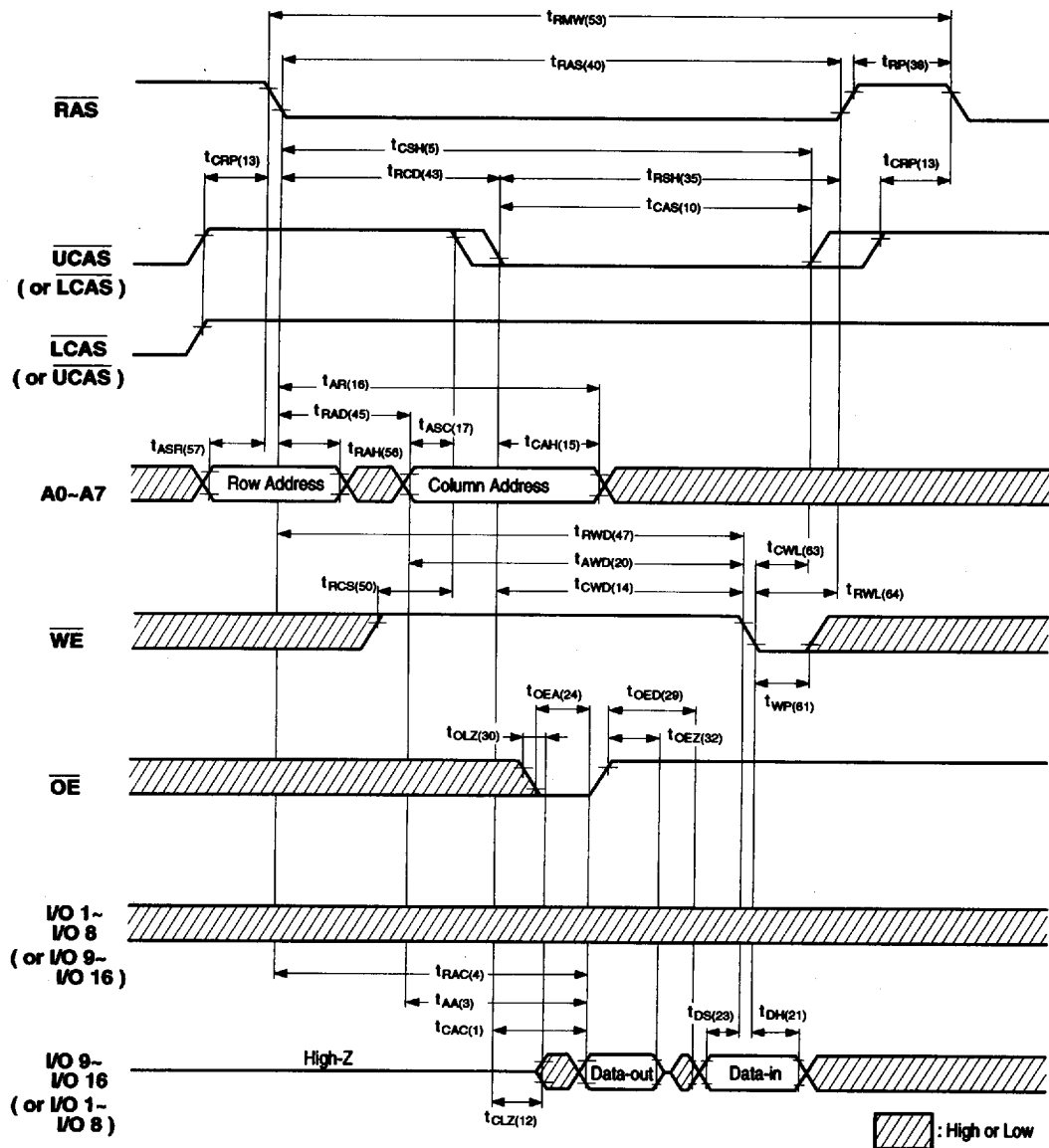
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WORD READ-MODIFY-WRITE CYCLE



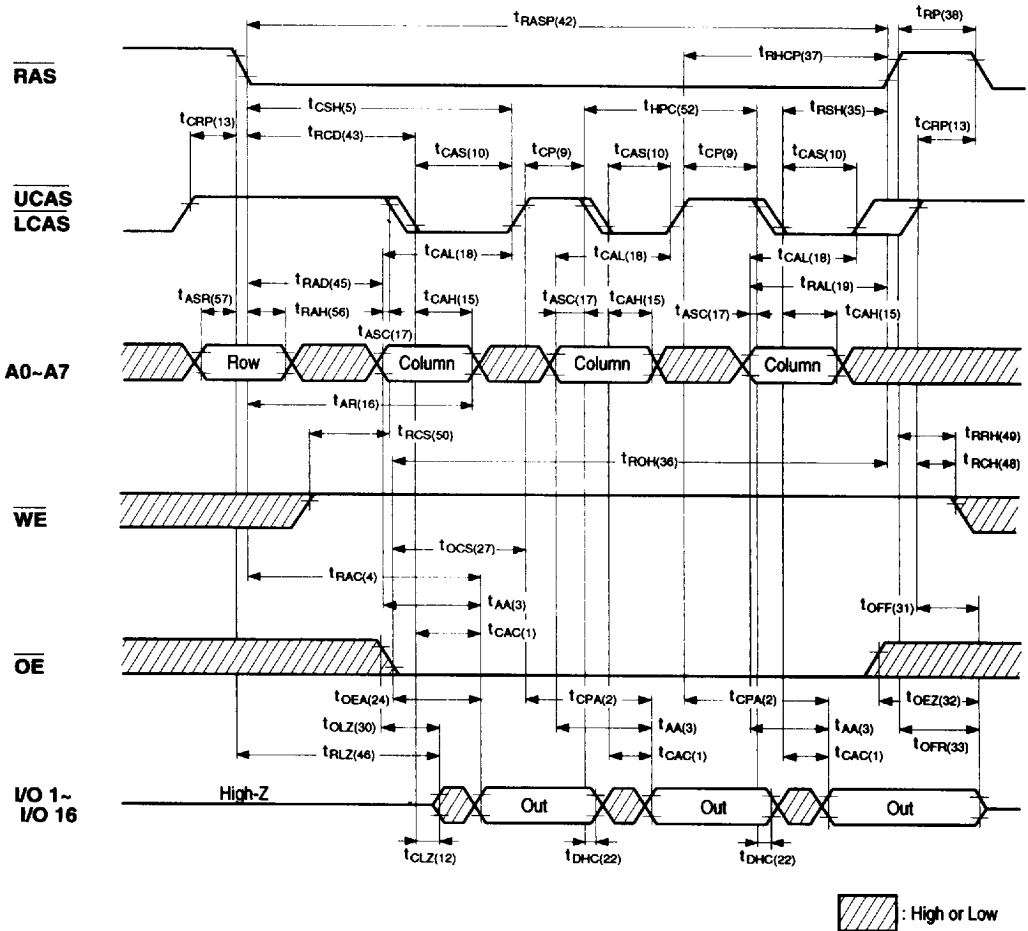
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BYTE READ-MODIFY-WRITE CYCLE



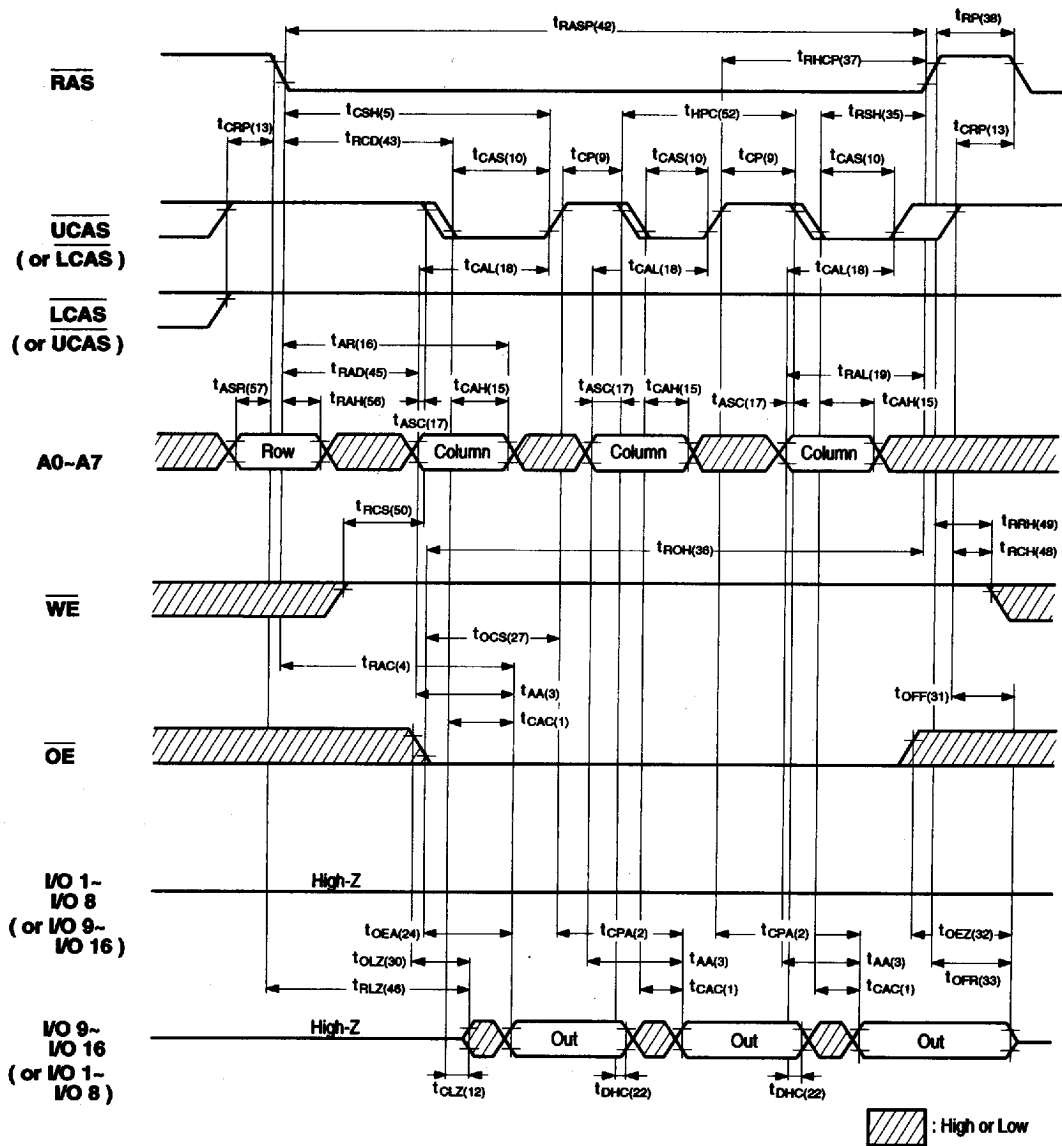
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EDO (HYPER PAGE) MODE WORD READ CYCLE



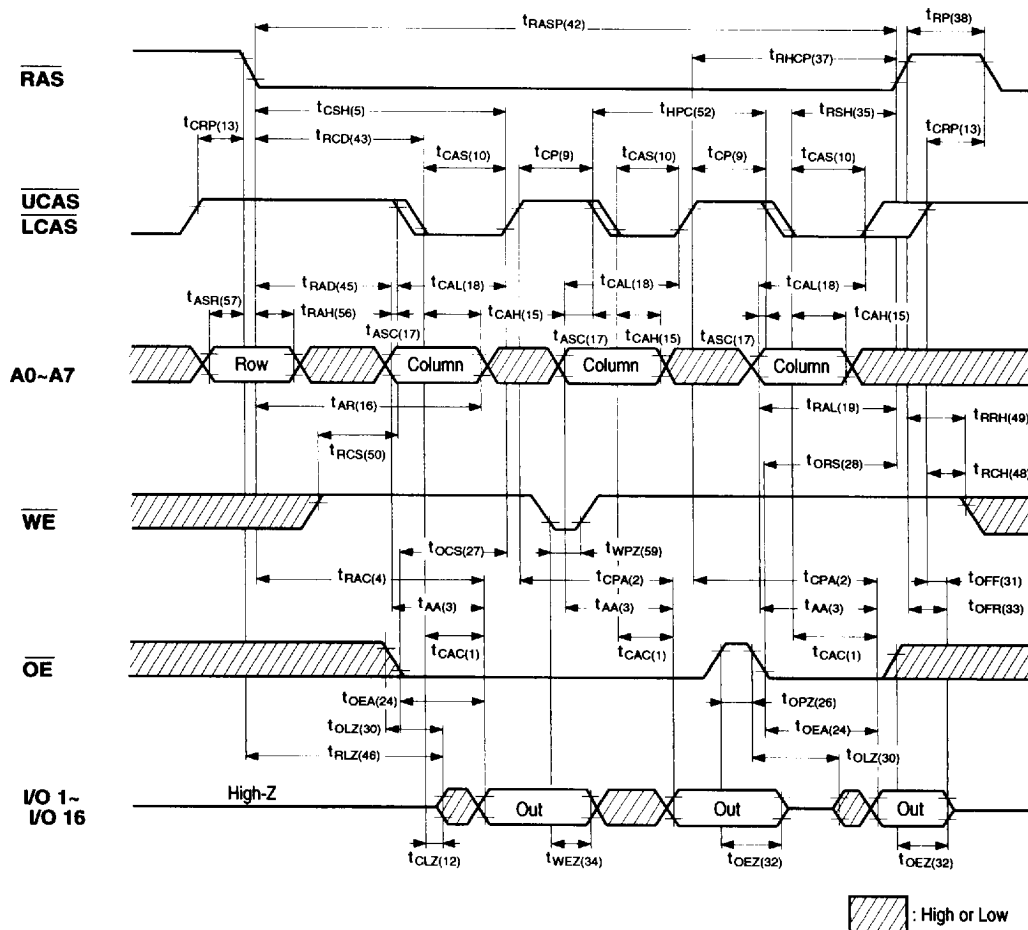
9005650 0001499 794

EDO (HYPER PAGE) MODE BYTE READ CYCLE



9005650 0001500 236

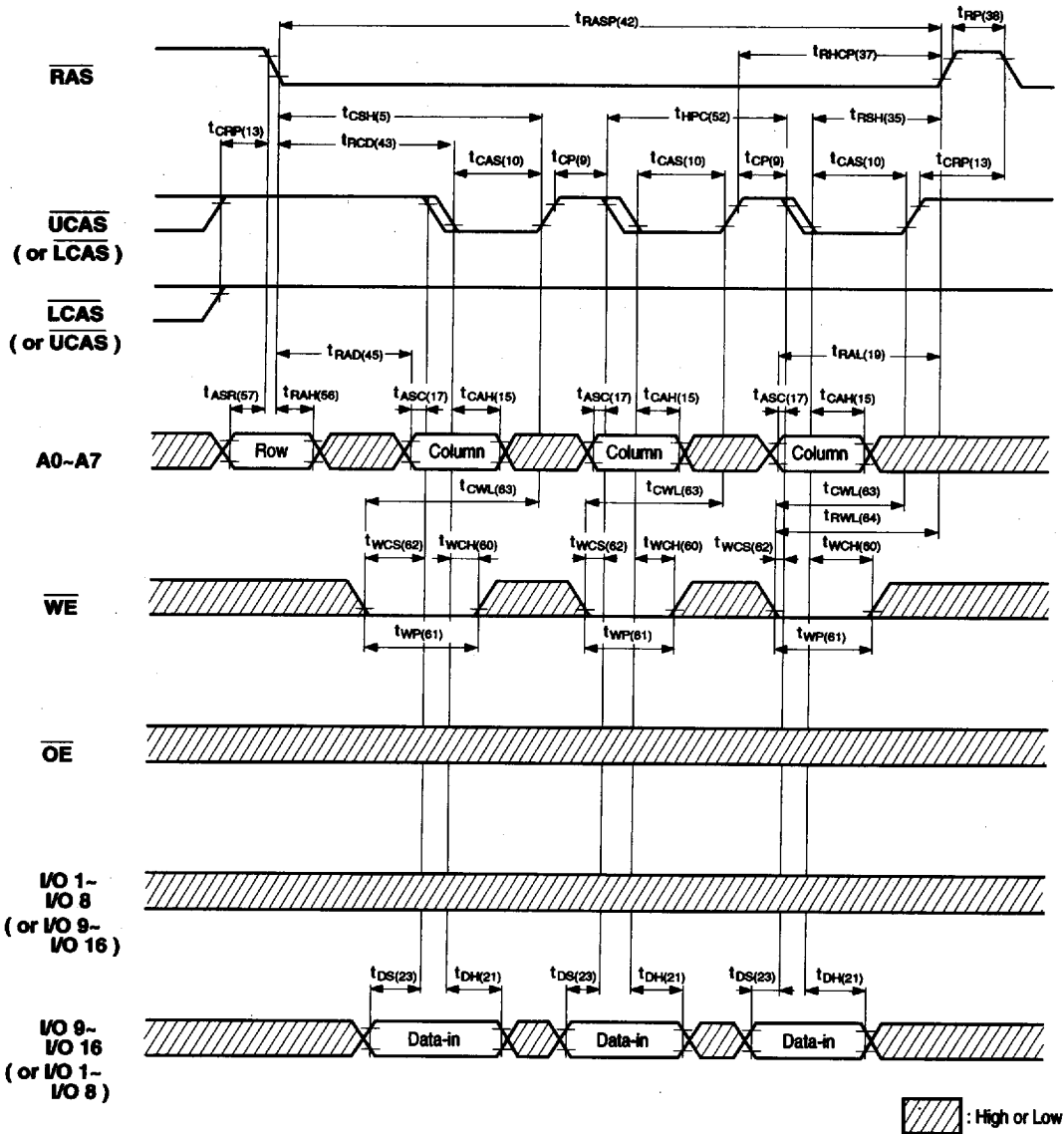
EDO (HYPER PAGE) MODE WORD READ CYCLE ($\overline{OE}$ AND $\overline{WE}$ CONTROLLED OUTPUT)



9005650 0001501 172



EDO (HYPER PAGE) MODE EARLY BYTE WRITE CYCLE



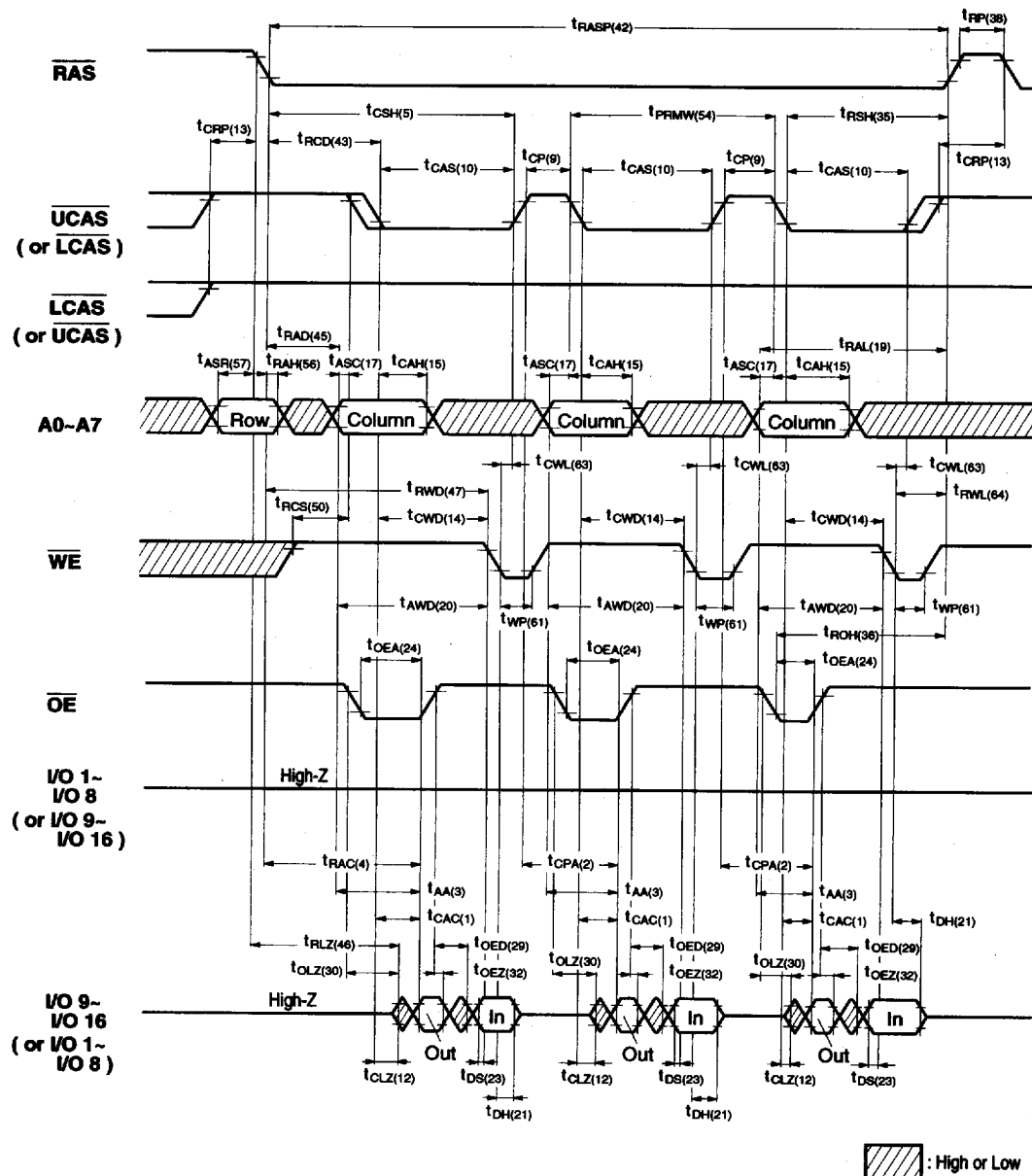
 : High or Low

NPNX

9005650 0001504 981

696

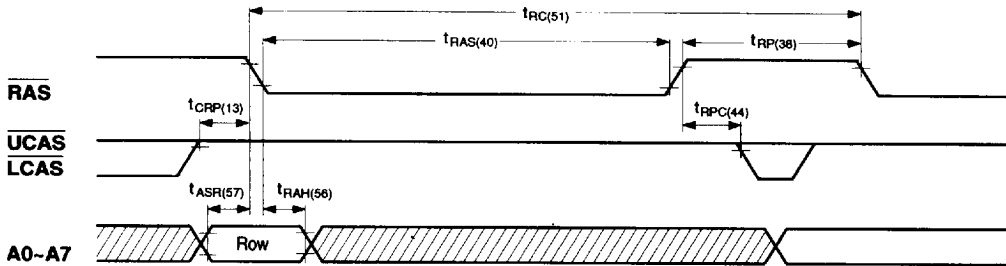
EDO (HYPER PAGE) MODE BYTE READ-MODIFY-WRITE CYCLE



9005650 0001506 754

NPNX

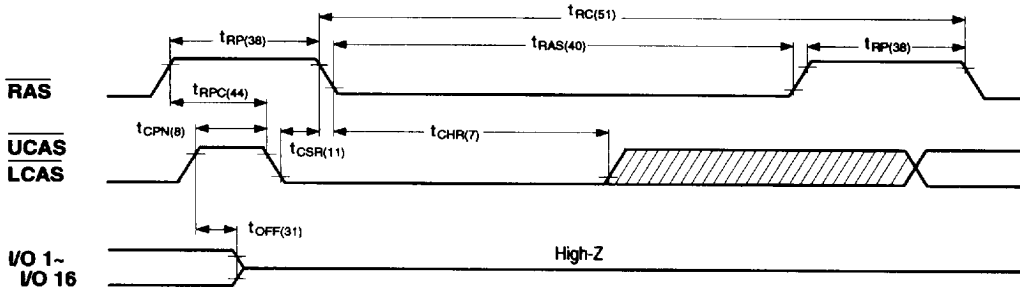
RAS ONLY REFRESH CYCLE



Note: $\overline{WE}$, $\overline{OE}$ = Don't care.

: High or Low

CAS BEFORE RAS REFRESH CYCLE

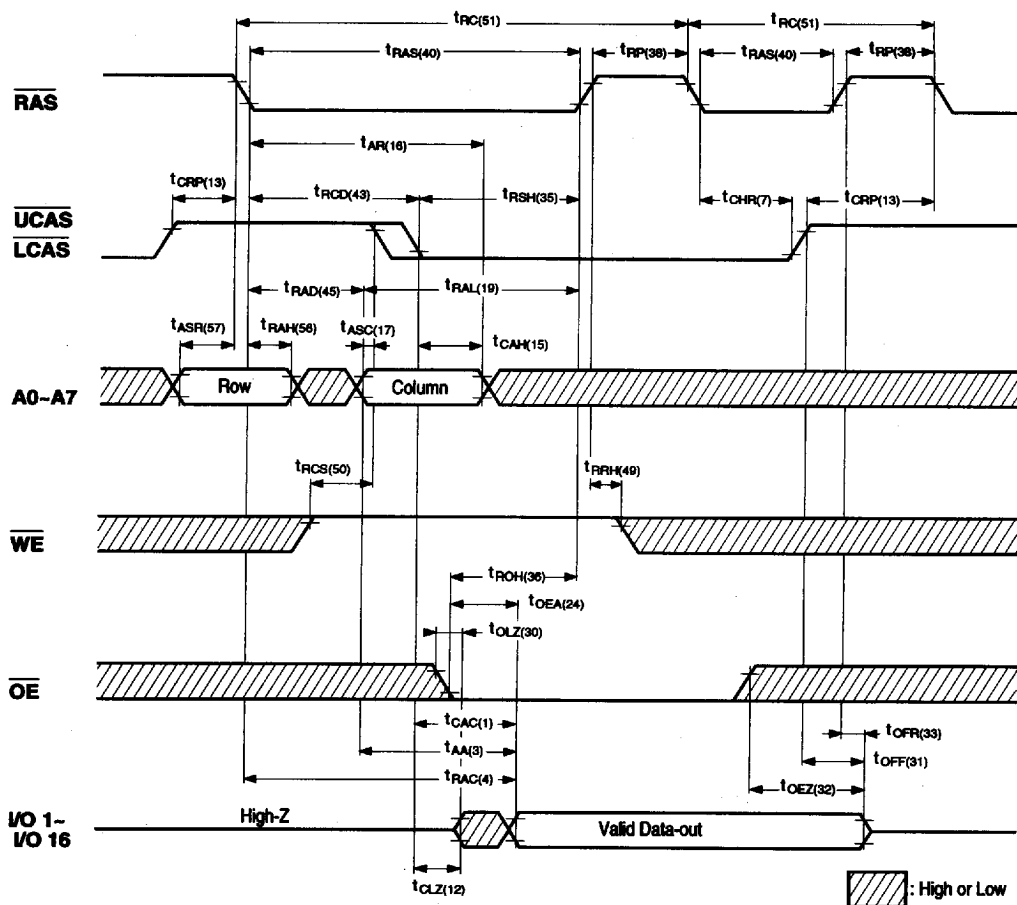


Note: $\overline{OE}$, A0~A7 = Don't care.

: High or Low

9005650 0001507 690

HIDDEN REFRESH CYCLE (WORD READ)

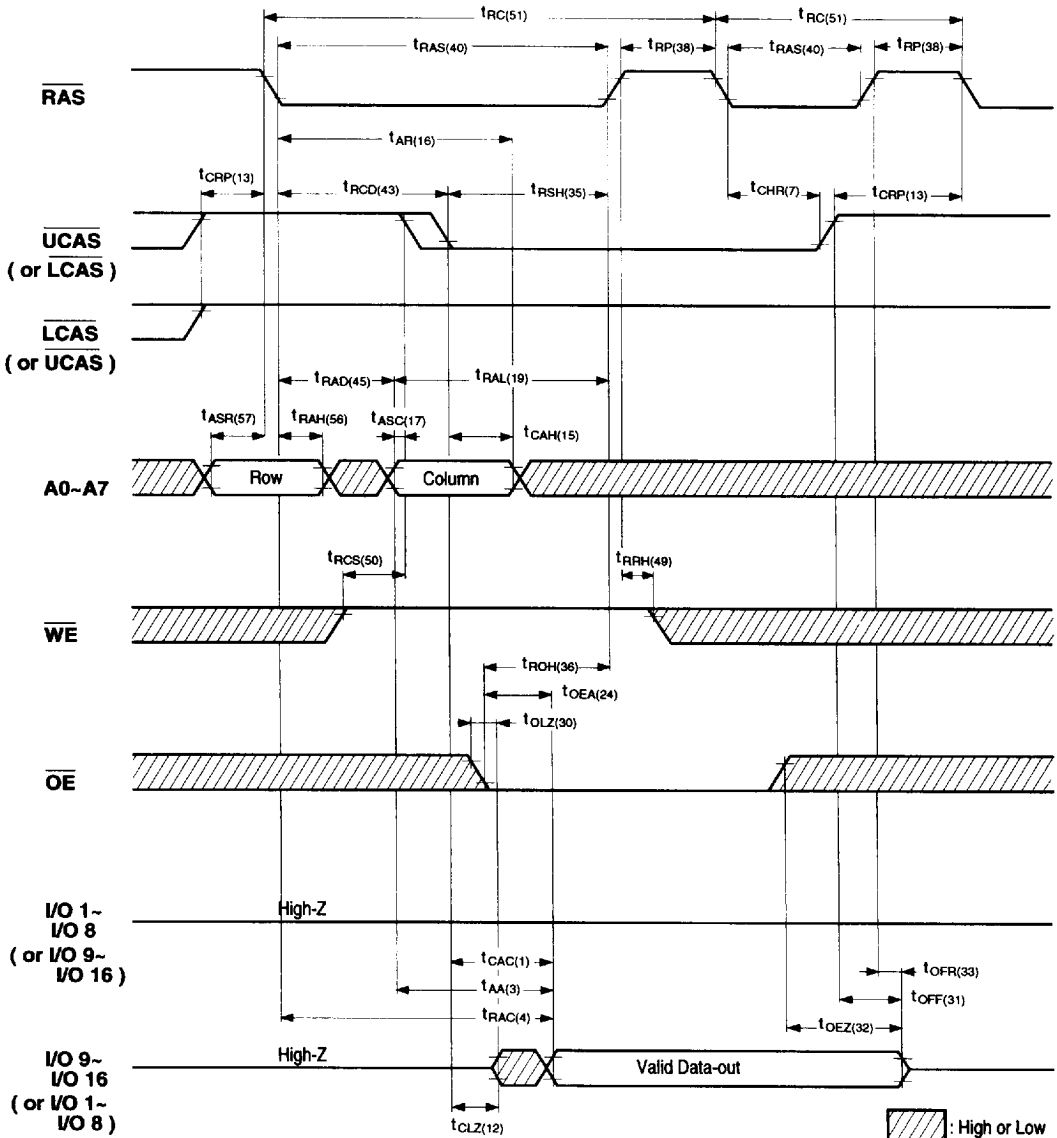


9005650 0001508 527

NPN

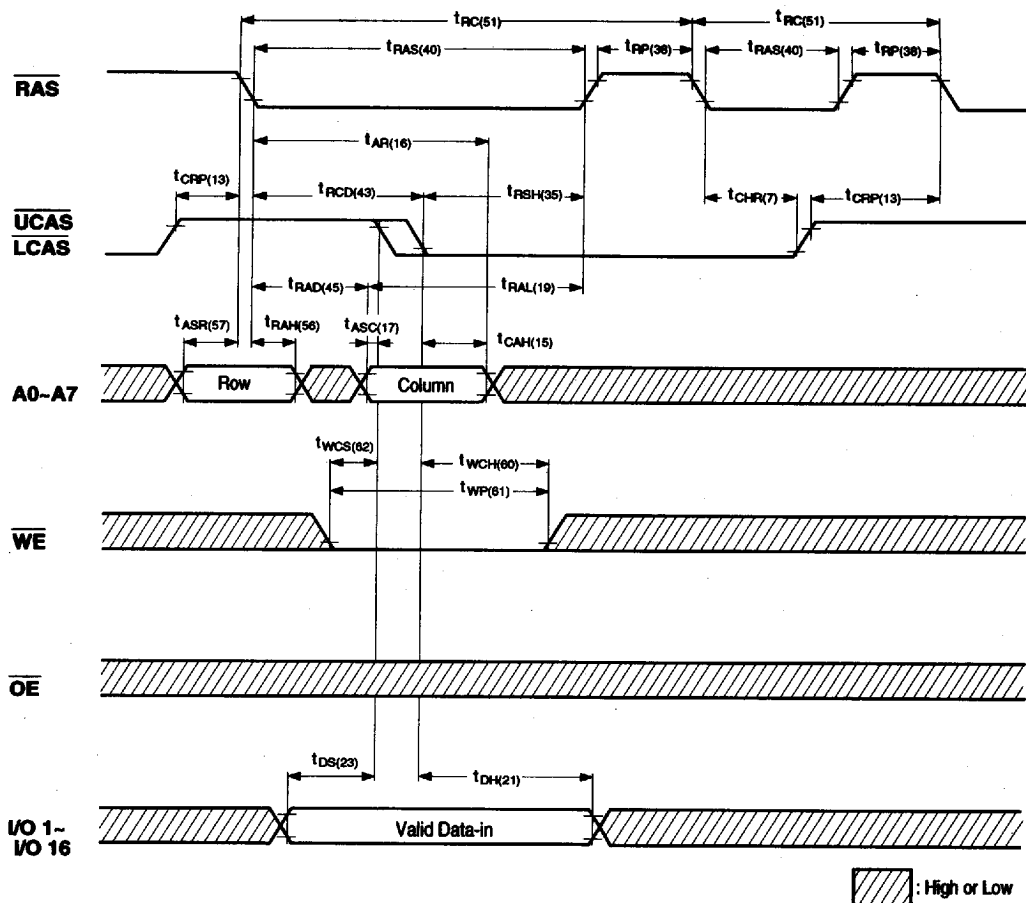
700

HIDDEN REFRESH CYCLE (BYTE READ)

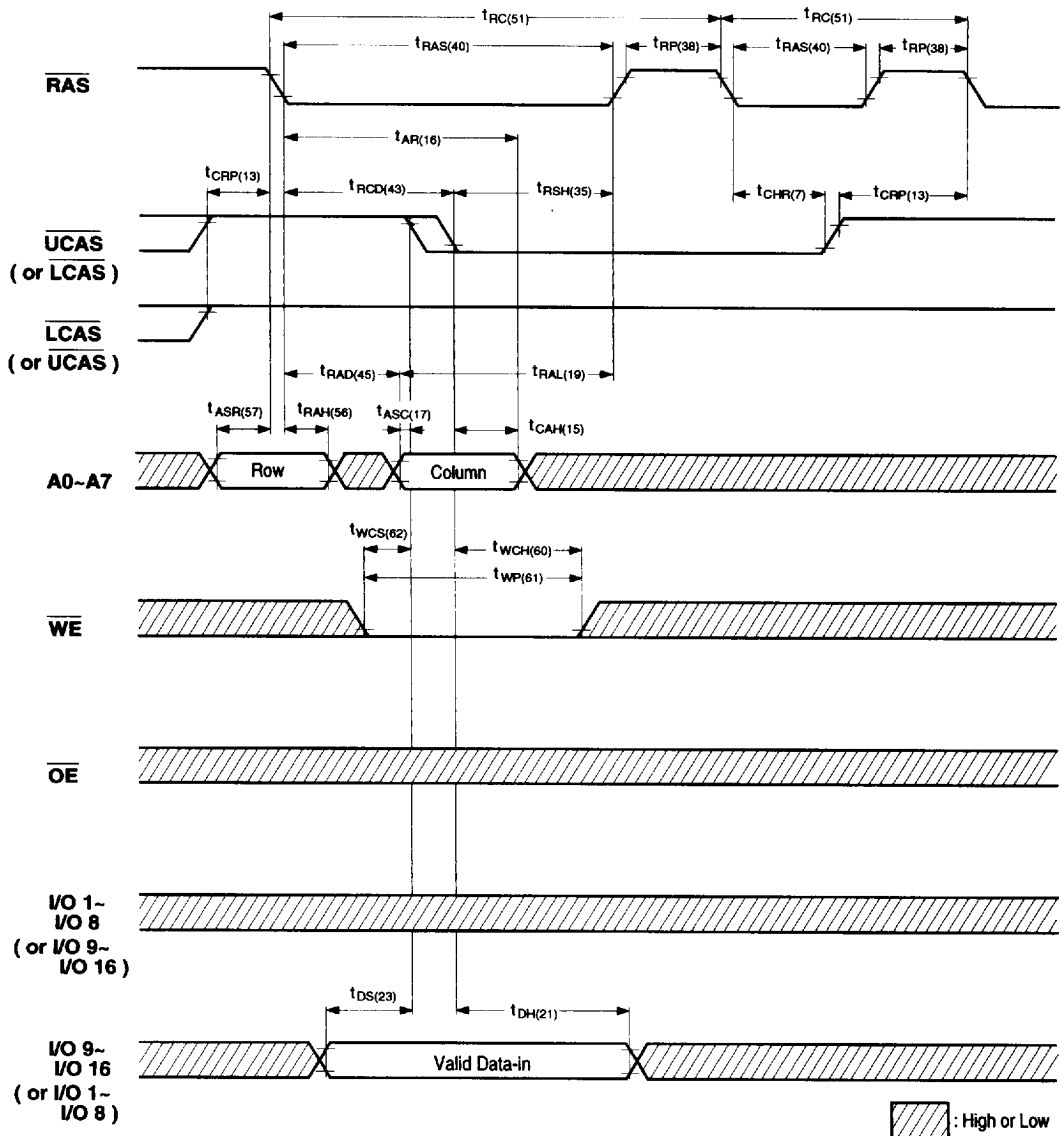


9005650 0001509 463

HIDDEN REFRESH CYCLE (EARLY WORD WRITE)

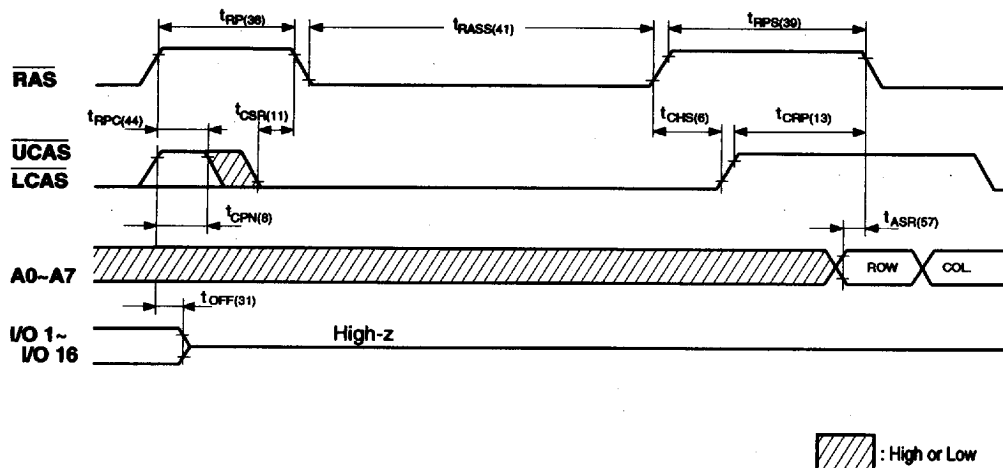


HIDDEN REFRESH CYCLE (EARLY BYTE WRITE)



9005650 0001511 011

SELF REFRESH MODE



■ The NN511661/1667 L version has a Self Refresh Mode.

a. Entering the Self Refresh Mode:

The NN511661L/1667L Self Refresh Mode is entered by using $\overline{CAS}$ before $\overline{RAS}$ cycle and holding $\overline{RAS}$ and $\overline{CAS}$ signal "low" longer than 300 μ s.

b. Continuing the Self Refresh Mode:

The Self Refresh Mode is continued by holding $\overline{RAS}$ "low" after entering the Self Refresh Mode. It does not depend on $\overline{CAS}$ being "high" or "low" after entering the Self Refresh Mode to continue the Self Refresh Mode.

c. Exiting the Self Refresh Mode:

The NN511661L/1667L exits the Self Refresh Mode when the $\overline{RAS}$ signal is brought "high".

■ 9005650 0001512 758 ■

ORDERING INFORMATION

NN511661XX(X) - XX

SPEED	40	:	40ns
	45	:	45ns
	50	:	50ns
	60	:	60ns
PACKAGE	J	:	Plastic SOJ
	TT	:	Plastic TSOP TYPEII
VERSION	BLANK	:	Standard Version
	L	:	Long Refresh Version
		:	32ms Refresh
MODE	1661	:	EDO (Hyper Page)
		:	2CAS,64K x 16 ,256 refresh cycle

NN511667XX(X) - XX

SPEED	40	:	40ns
	45	:	45ns
	50	:	50ns
	60	:	60ns
	70	:	70ns
PACKAGE	J	:	Plastic SOJ
	TT	:	Plastic TSOP TYPEII
VERSION	BLANK	:	Standard Version
	L	:	Long Refresh Version
		:	32ms Refresh
MODE	1667	:	EDO (Hyper Page)
		:	2CAS,64K x 16 ,256 refresh cycle